

Comparison of X-ray and Electron Beams for Structural, Chemical and Elemental Analysis

R.F. Egerton
Physics Department, University of Alberta,
Edmonton, Canada

The relative merits and problems associated with X-ray and electron-beam analysis have been reviewed many times previously [1 - 6]. We will try to make a current assessment of the situation in terms of the available instrumentation and the differences in physical properties of photons and electrons. In both cases, the basic limitations arise mainly from radiation damage, particularly for organic specimens.

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